

From virtual characterization to test-chips : DFM analysis through pattern enumeration

Martins, Mayler G.A.; **Pagliarini, Samuel Nascimento**; Isgenc, Mehmet Meric; Pileggi, Larry IEEE transactions on computer-aided design of integrated circuits and systems 2020 / p. 520-532 <https://doi.org/10.1109/TCAD.2018.2889772>

Hardware trojan insertion in finalized layouts : from methodology to a silicon demonstration

Perez, Tiago Diadami; Pagliarini, Samuel Nascimento IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems 2023 / p. 2094-2107 <https://doi.org/10.1109/TCAD.2022.3223846> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Impact of orientation on the bias of SRAM-based PUFs

Abideen, Zain Ul; Wang, Rui; Perez, Tiago Diadami; Schrijen, Geert-Jan; Pagliarini, Samuel Nascimento IEEE design & test 2024 / p. 14-20 <https://doi.org/10.1109/MDAT.2023.3322621> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Logic IP for low-cost IC design in advanced CMOS nodes

Isgenc, Mehmet Meric; Martins, Mayler G.A.; Zackriya, V. Mohammed; **Pagliarini, Samuel Nascimento**; Pileggi, Larry IEEE Transactions on Very Large Scale Integration (VLSI) Systems 2020 / p. 585-595 <https://doi.org/10.1109/TVLSI.2019.2942825>

PCB design impact on GaN-Based converter operation

Husev, Oleksandr; Jalakas, Tanel; Vinnikov, Dmitri; Vosoughi Kurdkandi, Naser; Persson, Eric 2023 IEEE Applied Power Electronics Conference and Exposition (APEC), 19-23 March 2023 : proceedings 2023 / p. 640-650 <https://doi.org/10.1109/APEC43580.2023.10131547> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)